



AT-60570
Up to 6 GHz Low Noise
Silicon Bipolar Transistor

T-31-19

Features

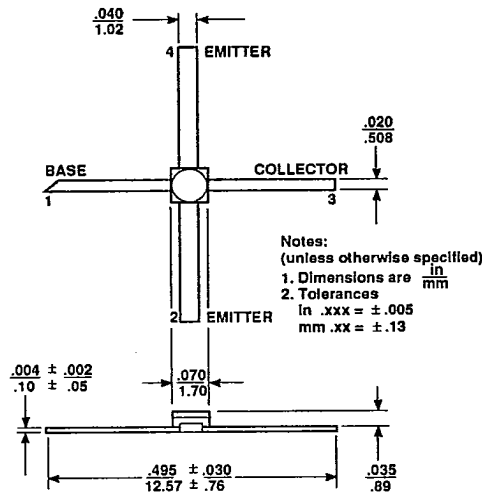
- Low Bias Current Operation:
- Low Noise Figure: 1.8 dB typical at 2.0 GHz
2.8 dB typical at 4.0 GHz
- High Associated Gain: 12.5 dB typical at 2.0 GHz
8.0 dB typical at 4.0 GHz
- High Gain-Bandwidth Product: 8.0 GHz typical f_T
- Hermetic Gold-ceramic Microstrip Package

Description

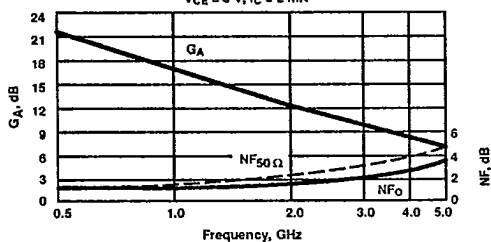
Avantek's AT-60570 is a high performance NPN silicon bipolar transistor housed in a hermetic, high reliability package. This device is designed for use in low noise, wide band amplifier and oscillator applications operating over VHF, UHF and microwave frequencies.

Excellent device uniformity, performance and reliability are produced by the use of ion-implantation, self-alignment techniques, and gold metallization in the fabrication of these devices.

Avantek 70 mil Package



NOISE FIGURE AND ASSOCIATED GAIN
vs. FREQUENCY
 $V_{CE} = 8 \text{ V}$, $I_C = 2 \text{ mA}$



Noise Parameters: $V_{CE} = 8 \text{ V}$, $I_C = 2 \text{ mA}$

Freq. GHz	NF ₀ dB	Gamma Opt Mag	Ang	R _N /50
1.0	1.4	.54	48	0.20
2.0	1.8	.44	98	0.28
4.0	2.8	.40	180	0.28

Electrical Specifications, $T_A = 25^\circ\text{C}$

Symbol	Parameters and Test Conditions	Units	Min.	Typ.	Max.
NF ₀	Optimum Noise Figure: $V_{CE} = 8 \text{ V}$, $I_C = 2 \text{ mA}$ $f = 1.0 \text{ GHz}$ $f = 2.0 \text{ GHz}$ $f = 4.0 \text{ GHz}$	dB		1.4 1.8 2.8	2.1
GA	Gain @ NF ₀ : $V_{CE} = 8 \text{ V}$, $I_C = 2 \text{ mA}$ $f = 1.0 \text{ GHz}$ $f = 2.0 \text{ GHz}$ $f = 4.0 \text{ GHz}$	dB	11.0	16.5 12.5 8.0	
S _{21E} ²	Insertion Power Gain: $V_{CE} = 8 \text{ V}$, $I_C = 10 \text{ mA}$ $f = 2.0 \text{ GHz}$ $f = 4.0 \text{ GHz}$	dB		12.0 6.5	
P ₁ dB	Power Output @ 1 dB Gain Compression: $V_{CE} = 8 \text{ V}$, $I_C = 10 \text{ mA}$ $f = 2.0 \text{ GHz}$	dBm		16.0	
G ₁ dB	1 dB Compressed Gain: $V_{CE} = 8 \text{ V}$, $I_C = 10 \text{ mA}$ $f = 2.0 \text{ GHz}$	dB		12.5	
f_T	Gain Bandwidth Product: $V_{CE} = 8 \text{ V}$, $I_C = 10 \text{ mA}$	GHz		8.0	
hFE	Forward Current Transfer Ratio: $V_{CE} = 8 \text{ V}$, $I_C = 10 \text{ mA}$		30	150	300
ICBO	Collector Cutoff Current: $V_{CB} = 8 \text{ V}$	μA			0.2
IEBO	Emitter Cutoff Current: $V_{EB} = 1 \text{ V}$	μA			1.0
C _{CB}	Collector Base Capacitance ¹ : $V_{CB} = 8 \text{ V}$, $f = 1 \text{ MHz}$	pF		0.15	

Note: 1. For this test the emitter is grounded.

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Absolute Maximum Ratings

Parameter	Symbol	Absolute Maximum ¹
Emitter-Base Voltage	V_{EB0}	1.5 V
Collector-Base Voltage	V_{CB0}	20 V
Collector-Emitter Voltage	V_{CE0}	12 V
Collector Current	I_C	40 mA
Power Dissipation ^{2,3}	P_T	400 mW
Junction Temperature	T_J	200°C
Storage Temperature	T_{STG}	-65°C to 200°C

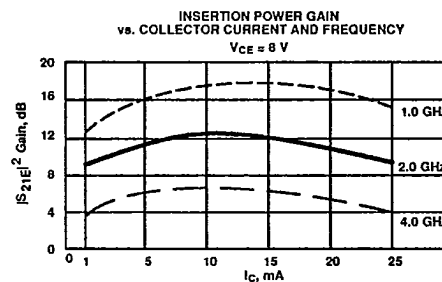
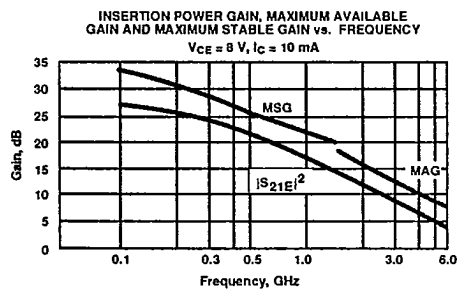
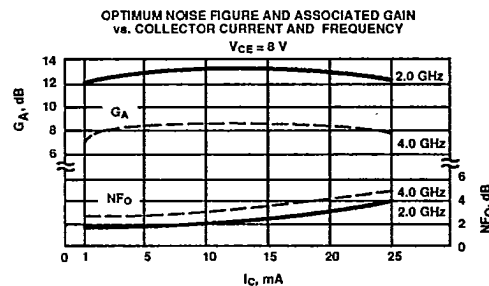
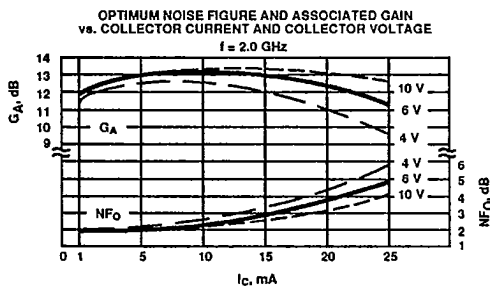
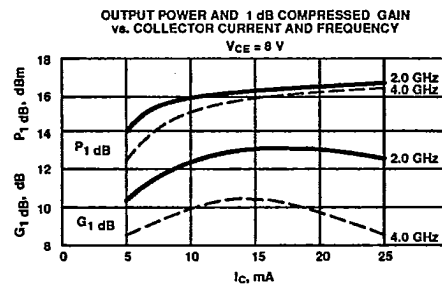
Thermal Resistance^{2,4}: $\theta_{JC} = 200^\circ\text{C/W}$

Notes:

- Operation of this device above any one of these parameters may cause permanent damage.
- $T_{CASE} = 25^\circ\text{C}$.
- Derate at $5 \text{ mW}/^\circ\text{C}$ for $T_C > 120^\circ\text{C}$.
- The small spot size of this technique results in a higher, though more accurate determination of θ_{JC} than do alternate methods. See MEASUREMENTS section "Thermal Resistance" for more information.

Typical Performance, $T_A = 25^\circ\text{C}$

(unless otherwise noted)



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Typical Scattering Parameters: Common Emitter, $Z_0 = 50 \Omega$ $T_A = 25^\circ\text{C}$, $V_{CE} = 8 \text{ V}$, $I_C = 2 \text{ mA}$

Freq. GHz	S_{11}		S_{21}			S_{12}			S_{22}	
	Mag	Ang	dB	Mag	Ang	dB	Mag	Ang	Mag	Ang
0.1	.95	-10	16.6	6.74	171	-38.4	.012	86	.99	-4
0.5	.86	-48	15.3	5.81	141	-27.2	.044	63	.92	-19
1.0	.72	-83	12.8	4.38	113	-23.0	.070	43	.81	-30
1.5	.62	-108	10.7	3.42	95	-22.0	.080	35	.74	-37
2.0	.56	-128	8.8	2.75	80	-21.2	.088	28	.70	-43
2.5	.52	-141	7.4	2.34	72	-20.6	.094	28	.67	-44
3.0	.51	-153	6.1	2.02	61	-20.8	.092	27	.66	-51
3.5	.51	-164	4.9	1.75	50	-20.4	.095	24	.67	-58
4.0	.49	-172	3.8	1.55	40	-20.0	.099	25	.67	-65
4.5	.48	-179	2.8	1.38	31	-19.8	.102	22	.69	-71
5.0	.46	-169	2.1	1.27	22	-19.5	.106	21	.69	-76
5.5	.44	-158	1.5	1.19	14	-19.2	.110	22	.70	-80
6.0	.44	-145	0.9	1.11	4	-18.4	.120	20	.69	-86

 $T_A = 25^\circ\text{C}$, $V_{CE} = 8 \text{ V}$, $I_C = 10 \text{ mA}$

0.1	.77	-26	27.3	23.25	161	-39.2	.011	79	.96	-9
0.5	.57	-98	22.6	13.51	116	-31.0	.028	49	.69	-27
1.0	.49	-136	17.8	7.72	92	-27.8	.041	45	.58	-31
1.5	.45	-156	14.6	5.36	79	-26.2	.049	45	.54	-34
2.0	.44	-171	12.3	4.10	69	-24.6	.059	48	.53	-39
2.5	.44	-177	10.5	3.35	63	-23.0	.070	51	.52	-39
3.0	.45	-174	9.1	2.84	55	-23.0	.071	52	.52	-47
3.5	.45	-167	7.8	2.46	46	-21.4	.086	52	.53	-56
4.0	.44	-160	6.7	2.16	37	-20.2	.097	50	.55	-63
4.5	.42	-153	5.7	1.92	29	-19.3	.108	47	.57	-70
5.0	.40	-144	4.9	1.75	21	-18.7	.116	44	.59	-75
5.5	.40	-132	4.2	1.62	13	-18.1	.124	41	.60	-79
6.0	.41	-121	3.5	1.49	4	-17.3	.137	38	.60	-86

A model for this device is available in the DEVICE MODELS section.